

November 1999 ADVANCE INFORMATION

FDZ2552P

Dual P-Channel 2.5V Specified PowerTrench[™] BGA MOSFET

General Description

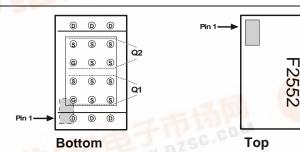
Combining Fairchild's advanced 2.5V specified PowerTrench process with state of the art BGA packaging, the FDZ2552P minimizes both PCB space and R_{DS(ON)}. This dual BGA MOSFET embodies a breakthrough in packaging technology which enables the device to combine excellent thermal transfer characteristics, high current handling capability, ultralow profile packaging, low gate charge, and low R_{DS(ON)}.

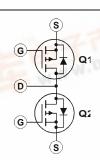
Applications

- · Battery management
- Load switch
- Battery protection

Features

- -6 A, -20 V. $R_{DS(ON)} = 0.045~\Omega~@~V_{GS} = -4.5~V$ $R_{DS(ON)} = 0.075~\Omega~@~V_{GS} = -2.5~V.$
- Occupies only 0.10 cm² of PCB area.
 1/3 the area of SO-8.
- Ultra-thin package: less than 0.70 mm height when mounted to PCB.
- Outstanding thermal transfer characteristics: significantly better than SO-8.
- Ultra-low Q_g x R_{DS(ON)} figure-of-merit.
- High power and current handling capability.





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		-20	V
V _{GSS}	Gate-Source Voltage		±12	V
I _D	Drain Current - Continuous	(Note 1a)	-6	Α
	Pulsed		-20	
P _D	Power Dissipation (Steady State)	(Note 1a)	3.0	W
T _J , T _{stg}	Operating and Storage Junction Temperature Range		-55 to +175	°C

Thermal Characteristics

R _{0JA}	Thermal Resistance, Junction-to-Ambient	(Note 1a)	50	°C/W
R _{eJC}	Thermal Resistance, Junction-to-Case	(Note 1)	8	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
F2552	FDZ2552P	TBD	TBD	TBD

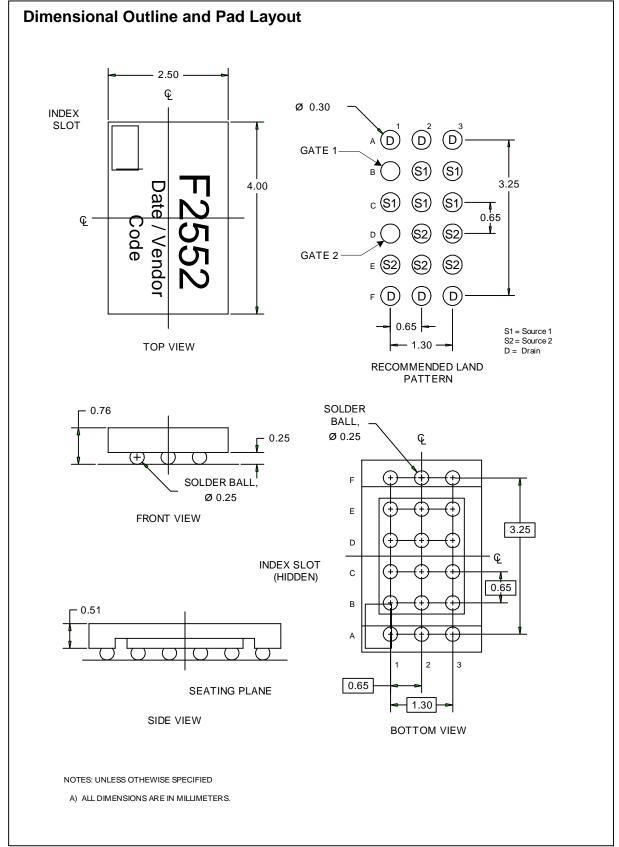
Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics	1			l .	I.
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-20			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = -250 \mu A$, Referenced to $25^{\circ}C$		28		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -16 \text{ V}, V_{GS} = 0 \text{ V}$			-1	μΑ
I _{GSSF}	Gate–Body Leakage Current, Forward	$V_{GS} = -12 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
I _{GSSR}	Gate–Body Leakage Current, Reverse	$V_{GS} = 12 \text{ V}$ $V_{DS} = 0 \text{ V}$			100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	-0.4	-0.9	-1.5	V
R _{DS(on)}	Static Drain–Source On–Resistance	$V_{GS} = -4.5 \text{ V}, I_D = -6 \text{ A}$ $V_{GS} = -2.5 \text{ V}, I_D = -4.5 \text{ A}$		0.036 0.060	0.045 0.075	Ω
Drain-S	ource Diode Characteristics a	and Maximum Ratings				
Is	Maximum Continuous Drain-Source	Diode Forward Current			-2.5	Α
V_{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -2.5 \text{ A} \text{(Note 2)}$		-0.77	-1.2	V

Notes:

R_{BJA} is a function of the junction-to-case (R_{BJC}), case-to-ambient (R_{BCA}) and the PC Board (R_{BBA}) thermal resistance where the case thermal reference is defined the top surface of the package. R_{BJC} is guaranteed by design while R_{BCA} and R_{BBA} are determined by the user's design. Maximum current ratings assume single device operation.

⁽a). $R_{\theta JA} = 50^{\circ} \text{C/W}$ (steady-state) when mounted on 1 in² of 2 oz. copper.

^{2.} Pulse Test: Pulse Width < 300μs, Duty Cycle < 2.0%





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